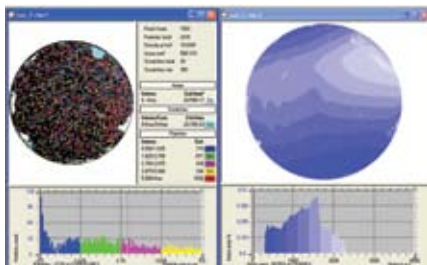


## WAFER INSPECTION



AWX 200



Cu/Si wafer: Particle and Haze Map

### AWX Series of Wafer Front Side, Back Side, and Edge Inspection Equipment

The **AWX Series** automated defect inspection product series for 200 mm, 300 mm and 450 mm unpatterned wafers. This modular tool consists of an automation platform with wafer transfer and sorting capability to be combined with up to two modules from the NanoPhotonics MetriCube series for front side, edge and back side inspection. Future metrology upgrades can easily be incorporated without changing the automation platform.

#### Applications

##### Front Side Inspection - FSI

- Laser dark field inspection detecting particles, scratches, area defects, and micro roughness (haze) on bare wafers.

##### Back Side Inspection- BSI

- High sensitivity dark field laser scattering system to detect particles, scratches, area defects, and haze at the wafer backside without flipping.

##### Edge Inspection - EDI

- CCD camera system with dark field / bright field LED illumination. It detects scratches, particles, chip-outs and roughness on the wafer edge.

##### Edge and Back Side Inspection - EBI

- Combines the back side wafer inspection module and the edge wafer inspection module for parallel operation of edge and back side wafer defect inspection.

##### Automatic Defect Classification – ADC

- Automatically classifies defects on the wafer back side and edge.


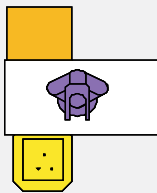
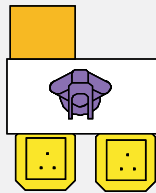


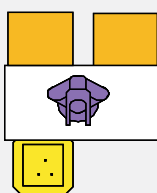
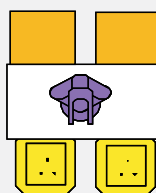

## WAFER INSPECTION



### AWX Features

- 300 mm silicon and glass wafers
- 200/300 mm bridge tool
- 450 mm Wafers
- Sorting capability
- Automatic defect classification

MetriCube® Bolts compatible Module – to be attached to the rear of the EFEM

Modules (MetriCube®)	Function	Configurations
 MC FSI	Front Side Inspection	<div style="display: flex; justify-content: space-around;"> <div style="text-align: center;"> <p>C11</p>  </div> <div style="text-align: center;"> <p>C12</p>  </div> </div>
 MC EDI	Edge Inspection	
 MC BSI	Back Side Inspection	<div style="display: flex; justify-content: space-around;"> <div style="text-align: center;"> <p>C21</p>  </div> <div style="text-align: center;"> <p>C22</p>  </div> </div>
 MC EBI	Edge and Back Side Inspection	